WEST

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Search Results -

Terms	Documents
L9 and BIST	3

Database:

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US Patents Full-Text Database
US Pre-Grant Publication Full-Text Database
JPO Abstracts Database
EPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins
```

Search: L14

Refine Search

Recall Text   Clear

09/747,734
Updated search

Examiner:
T. R. Sundaran

Search History

DATE: Monday, January 06, 2003   Printable Copy   Create Case

Set Name	Query	Hit Count	Set Name
	side by side		result set
	DB=USPT; THES=ASSIGNEE; PLUR=YES; OP=ADJ		
L14	L9 and BIST	3	L14
L13	L9 and predict$3 same (fail$3)	0	L13
L12	L9 and predict$3 and (fail$3)	22	L12
L11	L9 and predict with (fail$3)	0	L11
L10	L9 and predict with failure	0	L10
L9	L8 and (ris$3 or fall$3) with time	107	L9
L8	L7 and test ADJ signal	248	L8
L7	L6 and pulse ADJ width	958	L7
L6	(IC or integrated ADJ circuit) with (chip or die or dice) and test$3 with (signal or circuit)	10476	L6
L5	L3 and (predict$3 or forecast$3) with fail$3	3	L5
L4	L3 and predict$3 with fail$3	3	L4
L3	L2 and (ris$3 or fall$3) with signal	1271	L3
L2	L1 and pulse ADJ width	2848	L2
L1	(IC or integrated ADJ circuit) and test$3 with (signal or circuit)	28140	L1

END OF SEARCH HISTORY